

Electrogenerated Chemiluminescence Behavior of Graphite-like Carbon Nitride and Its Application in Selective Sensing Cu^{2+}

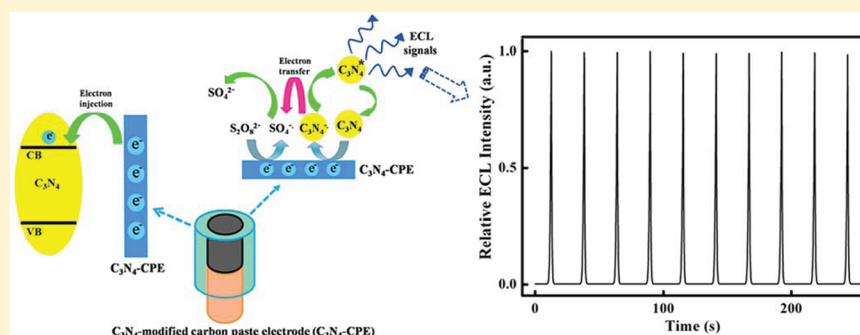
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S Supporting Information



ABSTRACT: This paper reports for the first time the electrogenerated chemiluminescence (ECL) behavior of graphite-like carbon nitride ($\text{g-C}_3\text{N}_4$) with $\text{K}_2\text{S}_2\text{O}_8$ as the coreactant. The possible ECL reaction mechanisms are proposed. The spectral features of the ECL emission and photoluminescence (PL) of $\text{g-C}_3\text{N}_4$ are compared, and their resemblance demonstrates that the excited states of $\text{g-C}_3\text{N}_4$ from both ECL and photoexcitation are the same. The effects of $\text{K}_2\text{S}_2\text{O}_8$ concentration, pH, $\text{g-C}_3\text{N}_4$ /carbon powder ratio, and scan rate on the ECL intensity have been studied in detail. Furthermore, it is observed that the ECL intensity is efficiently quenched by trace amounts of Cu^{2+} . $\text{g-C}_3\text{N}_4$ is thus employed to fabricate an ECL sensor which shows high selectivity to Cu^{2+} determination. The limit of detection is determined as 0.9 nM. It is anticipated that $\text{g-C}_3\text{N}_4$ could be a new class of promising material for fabricating ECL sensors.

In the present work, we report for the first time the electrogenerated chemiluminescence (ECL) of graphite-like carbon nitride ($\text{g-C}_3\text{N}_4$), which has recently attracted considerable attention attributing to its special structure and properties. Since $\text{g-C}_3\text{N}_4$ is a chemically and thermally stable semiconductor with a band gap of ca. 2.7 eV,¹ it has been explored for various applications, especially in the fields of catalysis and degradation.^{1–9} For instance, the generation of hydrogen from water could be realized by just the use of the inexpensive $\text{g-C}_3\text{N}_4$ as stable photocatalyst without any noble metals.¹ Furthermore, the semiconductor $\text{g-C}_3\text{N}_4$ exhibits good performance in hydrocarbon oxidation,^{2–4} carbon dioxide/oxygen reduction,⁵ organic dye degradation,^{6,7} phenol hydrogenation,⁸ and Friedel–Crafts reaction.⁹ It has also been reported that $\text{g-C}_3\text{N}_4$ exhibits photovoltaic/photocurrent effect, which is complement to other photoactive materials in the solar energy converting system.^{10,11} Additionally, an optical sensing system based on mesoporous $\text{g-C}_3\text{N}_4$ has been applied for detection of trace metal ions in aqueous solutions, where $\text{g-C}_3\text{N}_4$ as Lewis base shows high adsorption capacity for metal ions via chelation, initiating the promise for future biological and environmental monitoring.¹²

The ultraviolet–visible (UV–vis) absorption and photoluminescence (PL) spectra of $\text{g-C}_3\text{N}_4$ have been well-documented in previous reports.^{7,12,13} The absorption spectrum provides information about the band gap of this semiconductor, whereas the emission spectrum in the blue wavelength region implies that $\text{g-C}_3\text{N}_4$ could be utilized as an emitting material in light-emitting diodes and display devices. Recently, diverse semiconductors have been widely studied in the ECL field due to their unique ECL properties and potential applications in chemical sensors and biosensors.^{14–27} ECL exhibits attractive features over the PL technique because of its simpler design, lower cost, lower background emission, better controllability, and higher sensitivity.^{15,28–30} $\text{g-C}_3\text{N}_4$ possesses good chemical and thermal stability at ambient conditions,^{4,6,11} attributing to the strong covalent bonds between the carbon and nitrogen atoms. It is inexpensive and nontoxic and can be prepared by a simple thermal pyrolysis method. However, to the best of our knowledge, the ECL of $\text{g-C}_3\text{N}_4$ has never been

Received: January 19, 2012

Accepted: May 12, 2012

Published: May 12, 2012

reported. As such, it is our goal to investigate the ECL behavior of g-C₃N₄ and expand its potential applications in the analytical chemistry field.

In this work, the ECL measurements are conducted in 0.10 M potassium sulfate (K₂SO₄) aqueous solution containing potassium peroxydisulfate (K₂S₂O₈) as the coreactant by cyclic voltammetry (CV). The possible ECL reaction mechanisms are proposed. The electro-reduced g-C₃N₄ can readily react with a coreactant to produce an excited state which subsequently decays back to its ground state, emitting strong luminescence. The ECL displays a maximum emission peak at ca. 470 nm, which matches well with the PL spectrum of g-C₃N₄, suggesting that the same excited states are formed in both the electro-excitation and photoexcitation processes. Factors affecting the ECL response were studied carefully and the ECL working conditions were optimized. In addition, g-C₃N₄ could be used to fabricate an ECL sensor which shows high selectivity for detection of trace Cu²⁺ in nanomolar concentration. Cu²⁺ is a common pollutant in the environment. It is also a trace and essential element in biological systems.^{26,27,31} The application of this type of ECL sensor in real sample analysis is examined. The findings would open new avenues to construct ECL analytical systems based on semiconductor g-C₃N₄ material as it is stable and cost-effective.

EXPERIMENTAL SECTION

Chemicals. Melamine (2,4,6-triamino-1,3,5-triazine, 95%) was purchased from Kelong Chemical Co., Ltd. (Chengdu, China). Carbon powder (SP grade), potassium peroxydisulfate (AR grade), and potassium sulfate (AR grade) were obtained from Shanghai Chemical Reagent Co., Ltd. (Shanghai, China). All other reagents of analytical grade were used as received without further purification. Double distilled water was used throughout.

Synthesis of g-C₃N₄. g-C₃N₄ was prepared as described previously with some slight modifications.^{6,32} In brief, 5.0 g of white melamine powder was placed into a semiclosed ceramic crucible and heated at 823 K for 4 h in a muffle furnace under open air condition. Then, the sample was cooled to room temperature to obtain the yellow g-C₃N₄ product. It was ground to powder for further use.

Characterization. Powder X-ray diffraction (XRD) measurements were performed on a Tongda TD-3500 X-ray diffractometer (Dandong, Liaoning, China) with Cu K α radiation in a symmetric reflection setup. The PL and ECL emission spectra were recorded on a Hitachi F-7000 fluorescence spectrophotometer (Tokyo, Japan). The ECL behavior of g-C₃N₄ was investigated on a g-C₃N₄-modified carbon paste electrode. Herein, the carbon paste electrode was used as the working electrode owing to its broad potential window, low background current, chemical inertness, and ease of fabrication. Known quantities of carbon powder and g-C₃N₄ were thoroughly mixed with paraffin oil to obtain a homogeneous paste. Then, the paste was packed into a glass tube and connected to a copper wire for electrical contact. The electrode surface (2.0 mm in diameter) was polished with a piece of smooth paper before electrochemical measurements. For comparison, a pure carbon paste electrode without g-C₃N₄ was also prepared.

The CV and ECL measurements were conducted at 298 K in a classical three-electrode configuration consisting of a g-C₃N₄-modified carbon paste electrode working electrode, a platinum counter electrode, and an Ag/AgCl reference electrode. The

CV and ECL curves were recorded simultaneously using a MPI-E electrochemiluminescence analyzer system (Xi'an Remax Analysis Instrument Co., Ltd., Xi'an, China). The supporting electrolyte was 0.10 M K₂SO₄ with or without K₂S₂O₈ as the ECL coreactant. The photographic ECL image of g-C₃N₄ coated on a square indium tin oxide (ITO) glass plate was captured by a commercial digital camera in a dark environment.

RESULTS AND DISCUSSION

Synthesis and ECL Behavior of g-C₃N₄. In order to identify the phase structure of the as-synthesized sample, XRD measurement was conducted and is displayed in Figure S1 (Supporting Information). The XRD pattern is in good agreement with that of g-C₃N₄ in the previous report.⁶ In this study, the synthesis process was simplified by a one-step thermal-induced self-condensation of melamine under atmospheric environment and was done without the protection of inert gas. Figure 1 displays the ECL curves of the g-C₃N₄-

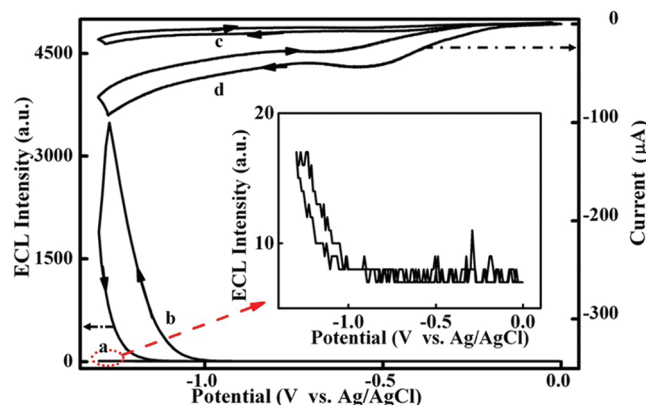
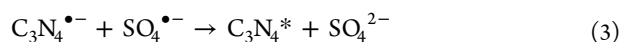
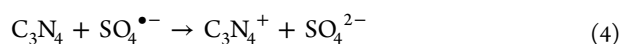


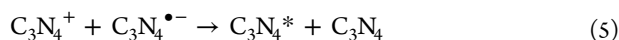
Figure 1. ECL–potential (a, b) and CV (c, d) curves of the g-C₃N₄-modified carbon paste electrode in 0.10 M K₂SO₄ without (a, c) and with (b, d) 3.0 mM K₂S₂O₈. The scan rate is 100 mV/s. The inset displays the enlarged view of curve a.

modified carbon paste electrode in the absence (curve a) and presence (curve b) of K₂S₂O₈ by cycling the potential between 0.00 and −1.30 V. An intense ECL emission is obtained on the g-C₃N₄-modified carbon paste electrode with 3.0 mM K₂S₂O₈. In contrast, only a very weak ECL is obtained without K₂S₂O₈ as shown in the inset of Figure 1. Obviously, these results confirm that the coreactant K₂S₂O₈ could greatly enhance the ECL intensity, inferring that S₂O₈^{2−} must play a crucial role in the ECL process. Two main ECL mechanisms, i.e., ion annihilation ECL and coreactant ECL, have been proposed in the literature.^{33–35} Analogous to the ECL pathways of other semiconductors and Au nanoclusters,^{29,34,36} the possible electrochemical reactions of g-C₃N₄ and S₂O₈^{2−} on the carbon paste electrode are as follows:



and/or





finally,



It has been reported that electrochemically reduced semiconductors could react with coreactants to produce ECL.^{18,23,36,37} Herein, an electron from the working electrode is injected to the conduction band of the semiconductor g-C₃N₄ to produce the negatively charged semiconductor g-C₃N₄ (i.e., g-C₃N₄^{•−}) (eq 1) during the cathodic potential scan as the potential is negative enough. Furthermore, there is evidence of electron injection to the conduction band of g-C₃N₄. For instance, electron from poly(3-hexylthiophene) can be injected into the conduction band of g-C₃N₄ in the photocatalytic hydrogen production process.³² The electronic band gaps of g-C₃N₄ have been previously explored, and the edge positions of the conduction band and the valence band are −0.83 and 1.83 V (vs NHE), respectively.¹⁰ As such, it is energetically possible for electron transfer from the carbon paste electrode to the conduction band of g-C₃N₄ if the applied potential on the working electrode is more negative than that of the conduction band of g-C₃N₄. Figure 1 depicts the CV curves of the g-C₃N₄-modified carbon paste electrodes in 0.10 M K₂SO₄ aqueous solution in the absence (curve c) and presence of K₂S₂O₈ (curve d). The reduction current increases sharply when the scan potential is more negative than ca. −1.00 V (vs Ag/AgCl) attributing to the electro-reduction of g-C₃N₄. For comparison, similar CV scans were conducted on the pure carbon paste electrode and are shown in Figure S2 (Supporting Information). The cathodic current is much smaller than that of the g-C₃N₄-modified carbon paste electrode. These data confirm the electron injection process shown in eq 1.

Figure 1 displays that a broad cathodic wave with a small shoulder peak at ca. −0.55 V (vs Ag/AgCl) is found for the g-C₃N₄-modified carbon paste electrode with K₂S₂O₈ (curve d). In contrast, a small cathodic wave without a shoulder peak is found when no K₂S₂O₈ is used (curve c). It is possible that S₂O₈^{2−} is electro-reduced to SO₄^{•−} and SO₄^{2−} (eq 2).^{29,38,39} Similar CV scans were conducted on the pure carbon paste electrode with K₂S₂O₈ (curve b in Figure S2, Supporting Information). A broad reduction peak of S₂O₈^{2−} at ca. −0.85 V (vs. Ag/AgCl) is observed which is more negative than that of the g-C₃N₄-modified carbon paste electrode (−0.55 V), indicating that S₂O₈^{2−} could be more favorably electro-reduced on the g-C₃N₄ semiconductor. The strong oxidant species (SO₄^{•−}) produced from electro-reduction during the cathodic scan (eq 2)^{40,41} would subsequently react with the reduced form of g-C₃N₄ to produce the excited state g-C₃N₄^{*} (g-C₃N₄^{*}) via electron transfer from g-C₃N₄^{•−} to SO₄^{•−} (eq 3). Another possible pathway for the generation of g-C₃N₄^{*} can be described by eqs 4 and 5. Since SO₄^{•−} is a very powerful oxidant, it may oxidize g-C₃N₄ to g-C₃N₄⁺ (eq 4) which is analogous to the formation of aromatic hydrocarbons radical cation upon oxidation by SO₄^{•−}.⁴² Subsequently, the annihilation of g-C₃N₄⁺ and g-C₃N₄^{•−} ions produces the ground state and excited state g-C₃N₄ (eq 5). Finally, an intense blue emission is obtained when g-C₃N₄^{*} decays back to the ground state g-C₃N₄ (eq 6). The onset potential for ECL is at ca. −1.00 V (vs Ag/AgCl), concurring with the electrochemical reduction of g-C₃N₄.

Figure 2A displays the PL spectrum of g-C₃N₄ solid powder at an excitation wavelength of 365 nm. A broad emission band

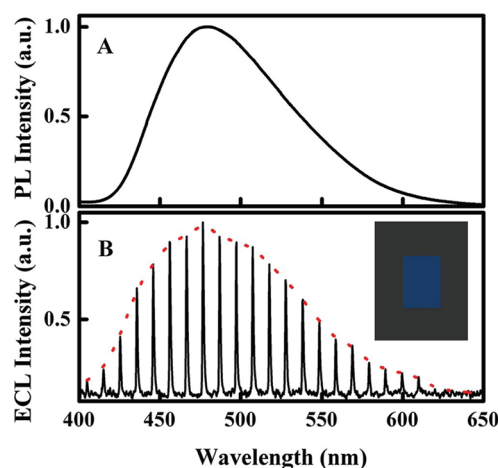


Figure 2. (A) PL spectrum of g-C₃N₄ solid powder when excited at 365 nm and (B) ECL spectrum of the g-C₃N₄-modified electrode in 0.10 M K₂SO₄ containing 3.0 mM K₂S₂O₈ by cycling the potential between 0.00 and −1.30 V (vs Ag/AgCl) with 1 mV step potential. The red curve is drawn across the ECL peaks to illustrate the ECL spectrum. The inset displays the photographic ECL image of g-C₃N₄ on an ITO glass.

at ca. 400–650 nm and an emission peak of ca. 470 nm are observed. The PL emission is derived from the electron–hole recombination process of g-C₃N₄ after the charge separation of the electron (in the conduction band) and the hole (in the valence band) upon photoexcitation.^{7,32} Figure 2B depicts the ECL spectrum of g-C₃N₄-modified electrode in 0.10 M K₂SO₄ and 3.0 mM K₂S₂O₈, recorded on a fluorescence spectrophotometer, with potentials cycling between 0.00 and −1.30 V at a scan rate of 100 mV/s and step potential of 1 mV. A red curve is drawn across all the peaks to better illustrate the ECL spectrum which matches closely with the PL band of g-C₃N₄. The energy of the ECL peak (ca. 470 nm, 2.6 eV) basically agrees with the optical band gap energy (2.7 eV), indicating that ECL emission is the band gap luminescence,⁷ which is consistent with other semiconductors.²¹ The ECL spectrum is slightly broader than the PL spectrum as a consequence of the differences in spectral measurements. The PL spectrum was recorded using g-C₃N₄ solid powder under photoexcitation whereas the ECL spectrum was acquired from a solution containing a coreactant. This is similar to our previous findings.⁴³ The spectral feature of ECL indicates that the excited-state g-C₃N₄ (g-C₃N₄^{*}) generated from the electrochemical reactions is similar to that from photoexcitation. The blue ECL emission from g-C₃N₄ is strong enough to be observed with naked eyes as shown in the inset of Figure 2B. The ECL intensities of the g-C₃N₄-modified carbon paste electrode in 0.10 M K₂SO₄ solution containing 3.0 mM K₂S₂O₈ and the carbon paste electrode in a standard solution of 0.10 M K₂SO₄ containing 3.0 mM K₂S₂O₈ and 1.0 mM Ru(bpy)₃²⁺ were compared. The ECL intensity of g-C₃N₄ is about 0.13 times of that of the standard solution (Figure S3, Supporting Information), demonstrating that our ECL sensor produces reasonable emission intensity.

Optimization of ECL Working Conditions. The ECL signal from the g-C₃N₄-modified carbon paste electrode is affected by several factors including K₂S₂O₈ concentration, solution pH, ratio of g-C₃N₄ to carbon powder (w/w), and CV scan rate. The ECL working conditions were optimized in this work. Figure 3A depicts the effect of K₂S₂O₈ concentration

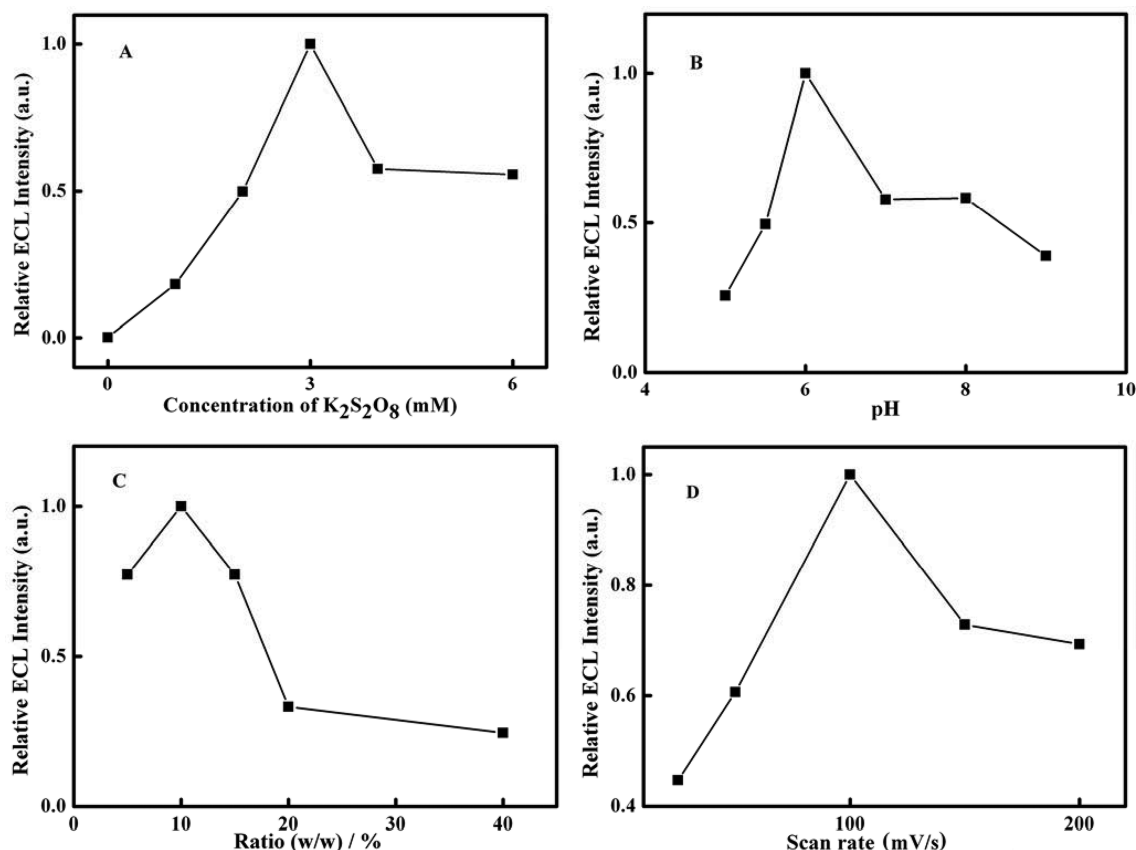


Figure 3. Effects of (A) $K_2S_2O_8$ concentration, (B) solution pH, (C) the ratio of g- C_3N_4 to carbon powder, and (D) scan rate on the ECL intensity of the g- C_3N_4 -modified carbon paste electrode.

(0.0–6.0 mM) on the ECL intensity of the g- C_3N_4 -modified carbon paste electrode. The ECL intensity increases significantly with the increase in $K_2S_2O_8$ concentration from 0.0 to 3.0 mM because more g- $C_3N_4^*$ is produced from oxidation of the negatively charged g- C_3N_4 by the electrogenerated $SO_4^{\bullet-}$. Further increase in $K_2S_2O_8$ concentration causes the decrease in ECL intensity as excess $S_2O_8^{2-}$ would react readily with the negatively charged g- C_3N_4 which inhibits the formation of the excited-state g- $C_3N_4^*$. A similar phenomenon was reported in the literature.^{38,41} As such, 3.0 mM was chosen as the optimal $K_2S_2O_8$ concentration and used throughout this work.

Figure 3B displays the effect of electrolyte pH (5.0–9.0) on the ECL intensity. The ECL intensity increases with the increase in pH 5.0–6.0 and then drops at high pH 6.0–9.0. At low pH, the proton could be reduced easily at the negative potential and the electro-reduction of g- C_3N_4 is inhibited. At too high pH, the strong oxidant $SO_4^{\bullet-}$ is consumed via the scavenging effect of OH^- .^{38,41,44} As a result, too low or high pH causes the decrease in the ECL intensity of the g- C_3N_4 -modified carbon paste electrode. Thus, pH 6.0 was chosen for this work as it would produce the strongest ECL emission.

The amount of g- C_3N_4 for fabrication of g- C_3N_4 -modified carbon paste was investigated. Figure 3C depicts the ECL intensities of various g- C_3N_4 -modified carbon paste electrodes with different ratios of g- C_3N_4 to carbon powder. The ECL intensity increases with the increase of g- C_3N_4 (5–10% w/w) and then decreases with further increase in g- C_3N_4 , attributing to the self-absorption effect of the luminophor.^{25,45} Since g- C_3N_4 exhibits strong absorption and ECL emission in the wavelength range of 300–450 nm^{1,7} and 400–650 nm (Figure

2B), respectively, there is a partial overlap of these spectra; thus, self-absorption occurs easily especially when the amount of g- C_3N_4 is high. As a result, 10% w/w g- C_3N_4 was used for fabrication of the g- C_3N_4 -modified carbon paste electrode.

Finally, the effect of scan rate on the ECL intensity was investigated and displayed in Figure 3D. The ECL intensity increases steadily with the increase in scan rate (25–100 mV/s) and then decreases at scan rates of 100–200 mV/s. These results are consistent with other ECL sensors.^{46,47} The ECL efficiency is governed by the formation rate of the excited-state species as well as the diffusion rate of the coreactant.⁴⁶ At high scan rates, the consumption of coreactant on the electrode interface would be much faster than the diffusion of the coreactant from the bulk solution to the electrode surface, leading to a low transient concentration of coreactant near the surface of the electrode with a concomitant decrease in ECL. In summary, too high of a scan rate would decrease the ECL; thus, 100 mV/s was selected as the optimal scan rate in this work.

Application of ECL from g- C_3N_4 . Operational stability is one of the major concerns for practical application of a sensor. Figure 4 displays the ECL emission of the g- C_3N_4 -modified carbon paste electrode under ten cycles of continuous potential scans between 0.00 and -1.30 V (vs Ag/AgCl) in 0.10 M K_2SO_4 (pH 6.0) and 3.0 mM $K_2S_2O_8$ at 100 mV/s. Strong and stable ECL signals are observed with a relative standard deviation of 0.36%. The results signify the excellent reversibility of the ECL signal, inferring its potential as an ECL sensor.

It was reported that the ECL emission based on other semiconductors could be quenched statically by Cu^{2+} .^{22,26} In this work, it is found that the ECL intensity of the g- C_3N_4 -

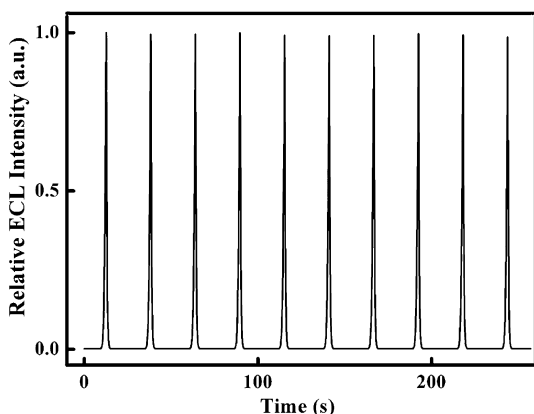


Figure 4. Stability of ECL emissions from the g-C₃N₄-modified carbon paste electrode under ten continuous cycles of CV scan.

modified carbon paste electrode is effectively quenched by trace amounts of Cu²⁺, demonstrating its potential for Cu²⁺ determination. Figure 5 presents the effect of various

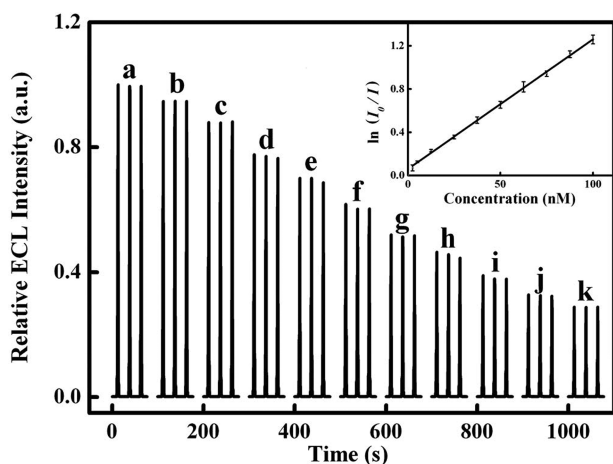


Figure 5. Effect of the concentration of Cu²⁺ (a) 0.0, (b) 2.5, (c) 5.0, (d) 12.5, (e) 25.0, (f) 37.5, (g) 50.0, (h) 62.5, (i) 75.0, (j) 87.5, and (k) 100.0 nM on the ECL intensity of the g-C₃N₄-modified carbon paste electrode. The inset displays the plot of $\ln(I_0/I)$ against the concentration of Cu²⁺, where I_0 and I are the ECL intensities in the absence and presence of Cu²⁺, respectively.

concentrations of Cu²⁺ on the ECL intensity of the g-C₃N₄-modified carbon paste electrode. Clearly, the ECL intensity decreases with the increase in Cu²⁺ concentration. Cu²⁺ could effectively quench the ECL of the g-C₃N₄-modified carbon paste electrode in the nanomolar range. The Poisson statistics static quenching model^{26,48,49} was employed to linearly relate the decrease in ECL intensity and concentration of Cu²⁺ by plotting $\ln(I_0/I)$ against the concentration of Cu²⁺ as shown in the inset of Figure 5, where I_0 and I are the ECL intensities in the absence and presence of Cu²⁺. The curve has a linear range from 2.5 to 100 nM with a detection limit of 0.9 nM ($S/N = 3$), which is lower than or comparable with other optical Cu²⁺ sensors based on semiconductor materials.^{12,22,26} The main attribute of the proposed ECL sensor is that the fabrication process is simple and cost-effective. More importantly, it exhibits potential for detection of Cu²⁺ in the subnanomolar level.

The selectivity of the present ECL sensor was also examined using common metal ions as potential interfering agents. The g-C₃N₄-modified carbon paste electrodes were exposed to these metal ions (100 nM) in 0.10 M K₂SO₄ (pH 6.0) and 3.0 mM K₂S₂O₈. Figure S4 (Supporting Information) reveals that the present ECL sensor has an excellent selectivity for Cu²⁺ over the other metal ions. Co²⁺, Zn²⁺, K⁺, Ca²⁺, Mg²⁺, Fe²⁺, Ni²⁺, Pb²⁺, and Cd²⁺ ions exhibit small quenching effects on the ECL signals which are similar to that of the PL measurement.¹² The proposed ECL sensor shows excellent selectivity to Cu²⁺ detection which could be attributed to the redox potential of Cu²⁺/Cu (0.159 V vs NHE) lying between the conduction (−0.83 V) and the valence bands (1.83 V) of g-C₃N₄ that allows efficient electron transfer from the negatively charged g-C₃N₄ to Cu²⁺, resulting in quenching of ECL.¹⁰ In addition, since the redox potential of Cu²⁺ is more positive than the other metal ions, the electron transfer between Cu²⁺ and g-C₃N₄ is more favorable than between other metal ions (i.e., Co²⁺, Zn²⁺, and Fe²⁺).

To further demonstrate the analytical reliability and real application of the developed ECL sensor, it was applied to determine the concentration of Cu²⁺ in a wastewater sample from a local factory. Wastewater sample (5.0 μL) was directly injected into the 5.0 mL ECL cell, and the decrease in ECL intensity was recorded and compared with a standard calibration curve. The Cu²⁺ content in the water sample was determined to be $36.8 \pm 0.6 \mu\text{M}$ ($n = 5$) which is consistent with the value (37.5 μM) obtained from an inductively coupled plasma-atomic emission spectroscopic method. These results indicate that the analytical performance of our proposed ECL sensor is good and can be applied to determine Cu²⁺ in real samples.

CONCLUSIONS

In summary, this paper reports for the first time the ECL responses of the semiconductor g-C₃N₄, demonstrating that it could be a new class of efficient and promising luminophore for ECL sensing. The possible reaction mechanisms for the ECL are proposed. Since the ECL signals could be effectively quenched by Cu²⁺, a new approach for sensitive and selective detection of Cu²⁺ has been successfully developed. This study offers an alternative, simple, and cost-effective technique for trace metal ion analysis.

ASSOCIATED CONTENT

Supporting Information

Supplementary figures of the XRD pattern, CV curves, chronoamperometry and ECL-time curves in the measurement of relative ECL efficiency, and comparison of the quenching effect of various metal ions on the g-C₃N₄-based ECL sensor. This material is available free of charge via the Internet at <http://pubs.acs.org>.

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Notes

The authors declare no competing financial interest.

■ ACKNOWLEDGMENTS

This work is financially supported by the National Natural Science Foundation of China (20927007, 21175094, and 21177090) and the Youth Foundation of Sichuan University (2010SCU11048). C. Cheng and Y. Huang contributed equally to this work.

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